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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
10/777,608	02/11/2004	Heinrich Ollendorf	2003P54807US (BHGL 10808/	•	
757	7590 02/23/2006		EXAMINER		
BRINKS H	OFER GILSON & LIO	GURLEY, LYNNE ANN			
P.O. BOX 10		A DOLLA LOUD	DADED AUTOER		
CHICAGO, IL 60610			ART UNIT	PAPER NUMBER	
			2812		
			DATE MAILED: 02/23/2006		

Please find below and/or attached an Office communication concerning this application or proceeding.

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	Application No.	Applicant(s)	
	10/777,608	OLLENDORF ET AL.	
Office Action Summary	Examiner	Art Unit	
	Lynne A. Gurley	2812	
The MAILING DATE of this communication app	ears on the cover sheet with the	correspondence address	s
Period for Reply		(O) OD TIUDTI ((O) T	
A SHORTENED STATUTORY PERIOD FOR REPLY WHICHEVER IS LONGER, FROM THE MAILING DA - Extensions of time may be available under the provisions of 37 CFR 1.1: after SIX (6) MONTHS from the mailing date of this communication. - If NO period for reply is specified above, the maximum statutory period v - Failure to reply within the set or extended period for reply will, by statute. Any reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b).	ATE OF THIS COMMUNICATION 36(a). In no event, however, may a reply be tinuity will apply and will expire SIX (6) MONTHS from a cause the application to become ABANDONE	N. mely filed In the mailing date of this commun ED (35 U.S.C. § 133).	
Status			
1) Responsive to communication(s) filed on 13 De	ecember 2005.		
·	action is non-final.		
3) Since this application is in condition for allowar		osecution as to the mer	its is
closed in accordance with the practice under E	·		
Disposition of Claims	·		
4) Claim(s) 1-9 is/are pending in the application.			
4a) Of the above claim(s) is/are withdraw	vn from consideration.		
5) Claim(s) is/are allowed.			
6)⊠ Claim(s) <u>1-9</u> is/are rejected.			
7) Claim(s) is/are objected to.			
8) Claim(s) are subject to restriction and/or	r election requirement.		
Application Papers			
9) The specification is objected to by the Examine	r.		
10) The drawing(s) filed on is/are: a) acce	epted or b) objected to by the	Examiner.	
Applicant may not request that any objection to the	drawing(s) be held in abeyance. Se	e 37 CFR 1.85(a).	
Replacement drawing sheet(s) including the correct			
11) The oath or declaration is objected to by the Ex	aminer. Note the attached Office	Action or form PTO-15	52.
Priority under 35 U.S.C. § 119			
12) Acknowledgment is made of a claim for foreign a) All b) Some * c) None of:	priority under 35 U.S.C. § 119(a)-(d) or (f).	
1. Certified copies of the priority documents	s have been received.		
2. Certified copies of the priority documents		ion No	
3. Copies of the certified copies of the prior	ity documents have been receive	ed in this National Stag	е
application from the International Bureau	ı (PCT Rule 17.2(a)).		
* See the attached detailed Office action for a list	of the certified copies not receive	ed. U.	
	Jy	A. GURLEY	
	LYNNI	PATENT EXAMINER	
Attachment(s)	PRIMARY TC 28	00, AU 2812	
Notice of References Cited (PTO-892)	4) Interview Summary		
2) Notice of Draftsperson's Patent Drawing Review (PTO-948)	Paper No(s)/Mail D	ate Patent Application (PTO-152)	
3) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08) Paper No(s)/Mail Date	6) Other:	Contribulous (FTO-132)	

DETAILED ACTION

This Office action is in response to the amendment filed 12/13/05.

Currently, claims 1-9 are pending.

Specification.

1. The lengthy specification has not been checked to the extent necessary to determine the presence of all possible minor errors. Applicant's cooperation is requested in correcting any errors of which applicant may become aware in the specification.

Claim Rejections - 35 USC § 102

2. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

- (b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.
- (e) the invention was described in (1) an application for patent, published under section 122(b), by another filed in the United States before the invention by the applicant for patent or (2) a patent granted on an application for patent by another filed in the United States before the invention by the applicant for patent, except that an international application filed under the treaty defined in section 351(a) shall have the effects for purposes of this subsection of an application filed in the United States only if the international application designated the United States and was published under Article 21(2) of such treaty in the English language.
- 3. Claims 16-19 are rejected under 35 U.S.C. 102(b) as being anticipated by Gupta et al. (US 6,114,243, dated 9/5/00).

Gupta shows the method as claimed in figures 1-17 and corresponding text, as a method for removal of chemical residues from a surface, the surface having a metal pattern 22/24/26 formed in a dielectric substrate 10/18 by a Chemical Mechanical Polishing (CMP) process (fig.

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14), the method comprising: plasma etching the surface to remove a predetermined thickness of the metal material (fig. 15).

4. Claims 16-19 are rejected under 35 U.S.C. 102(e) as being anticipate by Ngo et al. (US 6,818,557, dated 11/16/04, filed 12/12/02).

Ngo shows the method as claimed in figures 1-4 and corresponding text, as a method for removal of chemical residues from a surface, the surface having a metal pattern 13A formed in a dielectric substrate 10 by a Chemical Mechanical Polishing (CMP) process, the method comprising: plasma etching the surface to remove a predetermined thickness of the metal material (column 5, lines 49-62; column 8, lines 25-60).

Claim Rejections - 35 USC § 103

- 5. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 6. The factual inquiries set forth in *Graham* v. *John Deere Co.*, 383 U.S. 1, 148 USPQ 459 (1966), that are applied for establishing a background for determining obviousness under 35 U.S.C. 103(a) are summarized as follows:
 - 1. Determining the scope and contents of the prior art.
 - 2. Ascertaining the differences between the prior art and the claims at issue.
 - 3. Resolving the level of ordinary skill in the pertinent art.
 - 4. Considering objective evidence present in the application indicating obviousness or nonobviousness.

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7. This application currently names joint inventors. In considering patentability of the claims under 35 U.S.C. 103(a), the examiner presumes that the subject matter of the various claims was commonly owned at the time any inventions covered therein were made absent any evidence to the contrary. Applicant is advised of the obligation under 37 CFR 1.56 to point out the inventor and invention dates of each claim that was not commonly owned at the time a later invention was made in order for the examiner to consider the applicability of 35 U.S.C. 103(c) and potential 35 U.S.C. 102(e), (f) or (g) prior art under 35 U.S.C. 103(a).

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8. Claims 1-15 are rejected under 35 U.S.C. 103(a) as being unpatentable over Ngo et al. (US 6,818,557, dated 11/16/04, filed 12/12/02) in view of Padhi et al. (US 2004/0248409, dated 12/9/04, filed 3/30/04, provisional filed 6/3/03), further in view of Gupta et al. (US 6,114,243, dated 9/5/00).

Ngo shows the method substantially as claimed, in figures 1-4 and corresponding text, as: preparing the semiconductor surface 10/12/13 using a chemical mechanical polish (CMP) process (fig. 2), the surface defining an intended metal trench pattern 13A in a dielectric layer 10, the metal residue being located in an unintended scratch at the semiconductor surface (column 4, lines 66-67; column 5, lines 1-20); and exposing the prepared semiconductor surface to a plasma and an inert gas (column 5, lines 34-67; column 6, lines 1-49), the plasma having ions reacting with the metal residue, the surface being exposed to the plasma for a predetermined range of time.

Ngo lacks anticipation only in not teaching that the plasma has ions reacting with the metal residue to form a volatile gas; and the specific claimed chlorine, fluorine, and bromine

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etchants along with pressures, gas flow rates, and temperatures, depth of the scratch, depth of metal residue and range of time of exposure to the plasma.

Padhi teaches that plasma etching and fluorine vapors may be used instead of ammonia treatment to clean the substrate after CMP processing [0062]-[0063].

Gupta also teaches a conventional post CMP fluorine or chlorine etch (column 5, lines 10-20) which is "like a CMP over-polish process".

It would have been obvious to one of ordinary skill in the art to have cleaned the substrate, in the process of Ngo, by using a plasma chlorine or fluorine etchant as taught by Padhi and Gupta, with the motivation that since Padhi acknowledges that plasmas and fluorine chemistry may be used interchangeably to clean the substrate, use of the halogen etchants would produce a volatile gas. The specific claimed chlorine, fluorine, and bromine etchants along with pressures, gas flow rates, and temperatures, depth of the scratch, depth of metal residue and range of time of exposure to the plasma are obvious parameters of optimization of the process.

Response to Arguments

9. Applicant's arguments filed 12/13/05 have been fully considered but they are not persuasive. The prior art of record shows the claimed invention as previously shown.

Conclusion

10. The prior art made of record and not relied upon is considered pertinent to applicant's disclosure. See the previously cited PTO Form 892.

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11. Applicant's amendment necessitated the new ground(s) of rejection presented in this Office action. Accordingly, **THIS ACTION IS MADE FINAL**. See MPEP § 706.07(a). Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the date of this final action.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Lynne A. Gurley whose telephone number is 571-272-1670. The examiner can normally be reached on M-F 7:30-4:00.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Michael Lebentritt can be reached on 571-272-1873. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

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Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Lynne A. Gurley

Primary Patent Examiner

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LAG

February 21, 2006